

AMENDMENTS TO THE CLAIMS

1. (Currently Amended) A method of testing a memory die, comprising:
~~allowing said memory die to be placed in a location outside of a production~~
~~facility of said die;~~

testing said memory die ~~while said die is in said location;~~ and

storing at least a partial memory cell address on said die as a result of said
testing act, said address corresponding to a memory cell having failed said testing act,
~~wherein said address corresponds to a memory cell having failed said testing act~~

wherein said testing and storing acts are performed outside of a production
facility of said die.

2. (Original) The method in claim 1, wherein said testing act comprises testing
said die while said die is part of an electronic system.

3. (Original) The method in claim 2, wherein said testing act comprises testing
said die while said electronic system is in a power management mode.

4. (Original) The method in claim 2, wherein said testing act comprises testing
said die while said die is part of a computer system.

5. (Original) The method in claim 2, wherein said testing act comprises testing said die while said die is part of a telephone system.

6. (Original) The method in claim 5, wherein said testing act comprises testing said die while said die is part of a cellular telephone system.

7-63. (Canceled)

64. (New) A method of testing a memory die, comprising:

testing said memory die; and

storing at least a partial memory cell address on said die as a result of said testing act, said address corresponding to a memory cell having failed said testing act,

wherein said testing and storing acts are performed in the field.

65. (New) A method of testing a memory die, comprising:

testing said memory die; and

storing at least a partial memory cell address on said die as a result of said testing act, said address corresponding to a memory cell having failed said testing act,

wherein said testing and storing acts are performed when said die is part
of a processing system.